

**Notice of References Cited**

Application/Control No.

09/943,690

Applicant(s)/Patent Under

Reexamination

WEIER ET AL.

Examiner

Tae H. Yoon

Art Unit

1714

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-			
	D	US-			
	E	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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